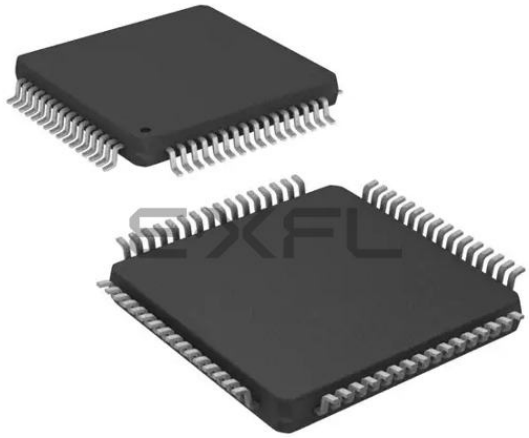

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	EBI/EMI, I²C, IrDA, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	50
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 28x12b; D/A 2x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/sim3c136-b-gqr

1. Related Documents and Conventions

1.1. Related Documents

This data sheet accompanies several documents to provide the complete description of the SiM3C1xx device family.

1.1.1. SiM3U1xx/SiM3C1xx Reference Manual

The Silicon Laboratories SiM3U1xx/SiM3C1xx Reference Manual provides detailed functional descriptions for the SiM3C1xx devices.

1.1.2. Hardware Access Layer (HAL) API Description

The Silicon Laboratories Hardware Access Layer (HAL) API provides C-language functions to modify and read each bit in the SiM3C1xx devices. This description can be found in the SiM3xxxx HAL API Reference Manual.

1.1.3. ARM Cortex-M3 Reference Manual

The ARM-specific features like the Nested Vector Interrupt Controller are described in the ARM Cortex-M3 reference documentation. The online reference manual can be found here:
http://infocenter.arm.com/help/topic/com.arm.doc.subset.cortexm.m3/index.html#cortexm3.

1.2. Conventions

The block diagrams in this document use the following formatting conventions:

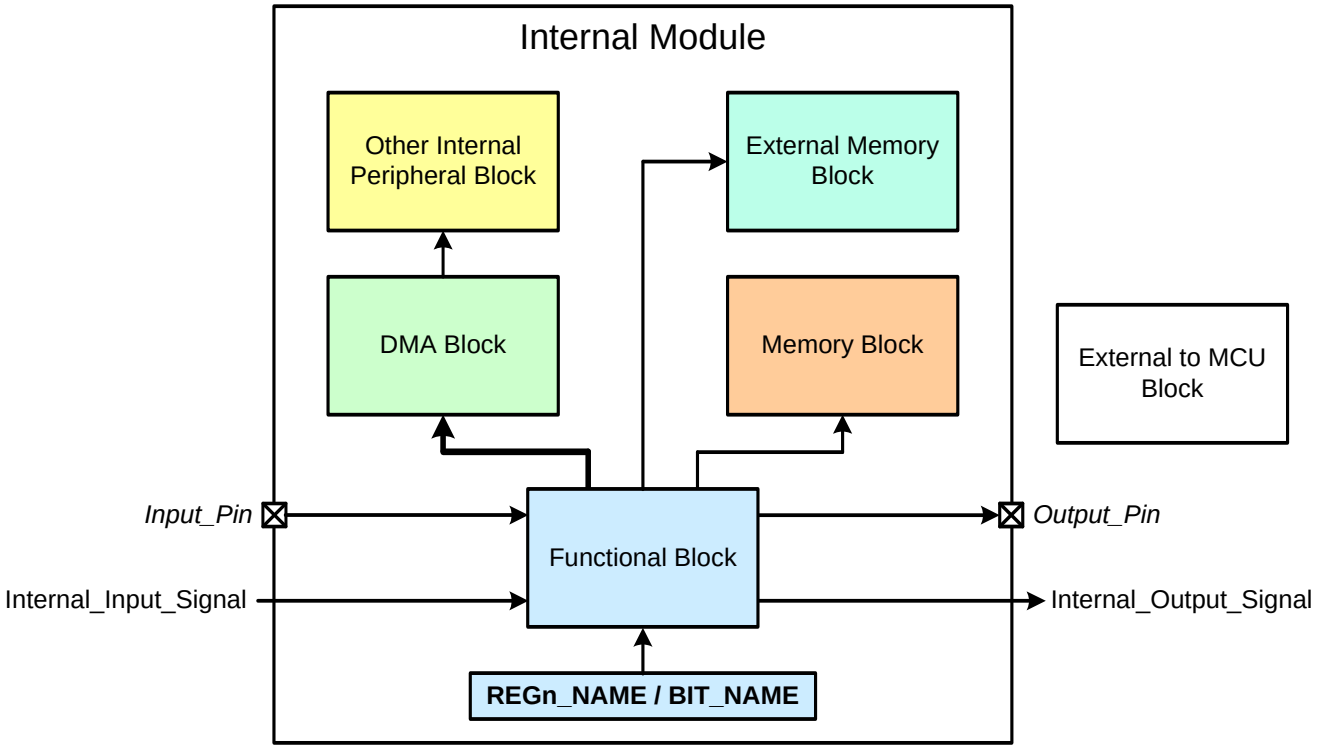


Figure 1.1. Block Diagram Conventions

Table 3.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current						
Normal Mode[2,3,4,5]—Full speed with code executing from Flash, peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	33	36.5	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	10.5	13.3	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	2.0	3.8	mA
Normal Mode[2,3,4,5]—Full speed with code executing from Flash, peripheral clocks OFF	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	22	24.9	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	7.8	10	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.2	3	mA
Power Mode 1[2,3,4,6]—Full speed with code executing from RAM, peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	30.5	35.5	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	8.5	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.7	—	mA
Power Mode 1[2,3,4,6]—Full speed with code executing from RAM, peripheral clocks OFF	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	20	23	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	5.3	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.0	—	mA
Power Mode 2[2,3,4]—Core halted with peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	19	22	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	7.8	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.3	—	mA
Power Mode 3[2,3]	I_{DD}	V_{DD} = 1.8 V, T_A = 25 °C	—	175	—	µA
		V_{DD} = 3.0 V, T_A = 25 °C	—	250	—	µA

Notes:
1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.2. Power Consumption (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Power Mode 9[2,3]—Low Power Shutdown with VREG0 disabled, powered through VDD and VIO	I_{DD}	RTC Disabled, V_{DD} = 1.8 V, T_A = 25 °C	—	85	—	nA
		RTC w/ 16.4 kHz LFO, V_{DD} = 1.8 V, T_A = 25 °C	—	350	—	nA
		RTC w/ 32.768 kHz Crystal, V_{DD} = 1.8 V, T_A = 25 °C	—	620	—	nA
		RTC Disabled, V_{DD} = 3.0 V, T_A = 25 °C	—	145	—	nA
		RTC w/ 16.4 kHz LFO, V_{DD} = 3.0 V, T_A = 25 °C	—	500	—	nA
		RTC w/ 32.768 kHz Crystal, V_{DD} = 3.0 V, T_A = 25 °C	—	800	—	nA
Power Mode 9[2,3]—Low Power Shutdown with VREG0 in low-power mode, VDD and VIO powered through VREG0 (Includes VREG0 current)	I_{VREGIN}	RTC Disabled, VREGIN = 5 V, T_A = 25 °C	—	300	—	nA
		RTC w/ 16.4 kHz LFO, VREGIN = 5 V, T_A = 25 °C	—	650	—	nA
		RTC w/ 32.768 kHz Crystal, VREGIN = 5 V, T_A = 25 °C	—	950	—	nA
VIOHD Current (High-drive I/O disabled)	I_{VIOHD}	HV Mode (default)	—	2.5	5	µA
		LV Mode	—	2	—	nA

Notes:

1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.4. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
V_{DD} High Supply Monitor Threshold (VDDHITHEN = 1)	V_{VDDMH}	Early Warning	2.10	2.20	2.30	V
		Reset	1.95	2.05	2.1	V
V_{DD} Low Supply Monitor Threshold (VDDHITHEN = 0)	V_{VDDML}	Early Warning	1.81	1.85	1.88	V
		Reset	1.70	1.74	1.77	V
V_{REGIN} Supply Monitor Threshold	V_{VREGM}	Early Warning	4.2	4.4	4.6	V
Power-On Reset (POR) Threshold	V_{POR}	Rising Voltage on V_{DD}	—	1.4	—	V
		Falling Voltage on V_{DD}	0.8	1	1.3	V
V_{DD} Ramp Time	t_{RMP}	Time to $V_{DD} \geq 1.8$ V	10	—	3000	µs
Reset Delay from POR	t_{POR}	Relative to $V_{DD} \geq V_{POR}$	3	—	100	ms
Reset Delay from non-POR source	t_{RST}	Time between release of reset source and code execution	—	10	—	µs
$\overline{\text{RESET}}$ Low Time to Generate Reset	t_{RSTL}		50	—	—	ns
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	$F_{AHB} > 1$ MHz	—	0.4	1	ms
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7.5	13	kHz
V_{DD} Supply Monitor Turn-On Time	t_{MON}		—	2	—	µs

Table 3.5. On-Chip Regulators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
3.3 V Regulator Characteristics (VREG0, Supplied from VREGIN Pin)						
Output Voltage (at VDD pin)	V_{DDOUT}	$4 \le V_{REGIN} \le 5.5$ BGDIS = 0, SUSEN = 0	3.15	3.3	3.4	V
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 0, SUSEN = 1	3.15	3.3	3.4	V
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 1, SUSEN = X I_{DDOUT} = 500 µA	2.3	2.8	3.6	V
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 1, SUSEN = X I_{DDOUT} = 5 mA	2.1	2.65	3.3	V
Output Current (at VDD pin)*	I_{DDOUT}	$4 \le V_{REGIN} \le 5.5$ BGDIS = 0, SUSEN = X	—	—	150	mA
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 1, SUSEN = X	—	—	5	mA
Output Load Regulation	V_{DDLR}	BGDIS = 0	—	0.1	1	mV/mA
Output Capacitance	C_{VDD}		1	—	10	µF

***Note:** Total current VREG0 is capable of providing. Any current consumed by the SiM3C1xx reduces the current available to external devices powered from VDD.

Table 3.8. Internal Oscillators (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Low Power Oscillator (LPOSC0)						
Oscillator Frequency	f_{LPOSC}	Full Temperature and Supply Range	19	20	21	MHz
		T_A = 25 °C, V_{DD} = 3.3 V	19.5	20	20.5	MHz
Divided Oscillator Frequency	f_{LPOSCD}	Full Temperature and Supply Range	2.375	2.5	2.625	MHz
Power Supply Sensitivity	PSS_{LPOSC}	T_A = 25 °C	—	0.5	—	%/V
Temperature Sensitivity	TS_{LPOSC}	V_{DD} = 3.3 V	—	55	—	ppm/°C
Low Frequency Oscillator (LFOSC0)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	13.4	16.4	19.7	kHz
		T_A = 25 °C, V_{DD} = 3.3 V	15.8	16.4	17.3	kHz
Power Supply Sensitivity	PSS_{LFOSC}	T_A = 25 °C	—	2.4	—	%/V
Temperature Sensitivity	TS_{LFOSC}	V_{DD} = 3.3 V	—	0.2	—	%/°C
RTC0 Oscillator (RTC0OSC)						
Missing Clock Detector Trigger Frequency	f_{RTCMCD}		—	8	15	kHz
RTC Robust Duty Cycle Range	DC_{RTC}		25	—	55	%
***Note:** PLL0OSC in free-running oscillator mode.						

Table 3.9. External Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency*	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns
External Crystal Clock Frequency	f_{XTAL}		0.01	—	30	MHz
***Note:** Minimum of 10 kHz during debug operations.						

Table 3.17. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Standard I/O (PB0, PB1, and PB2), 5 V Tolerant I/O (PB3), and $\overline{\text{RESET}}$						
Output High Voltage*	V_{OH}	Low Drive, I_{OH} = –2 mA	V_{IO} – 0.7	—	—	V
		High Drive, I_{OH} = –5 mA	V_{IO} – 0.7	—	—	V
Output Low Voltage*	V_{OL}	Low Drive, I_{OL} = 3 mA	—	—	0.6	V
		High Drive, I_{OL} = 12.5 mA	—	—	0.6	V
Input High Voltage	V_{IH}	1.8 ≤ V_{IO} ≤ 2.0	0.7 x V_{IO}	—	—	V
		2.0 ≤ V_{IO} ≤ 3.6	V_{IO} – 0.6	—	—	V
Input Low Voltage	V_{IL}		—	—	0.6	V
Pin Capacitance	C_{IO}	PB0, PB1 and PB2 Pins	—	4	—	pF
		PB3 Pins	—	7	—	pF
Weak Pull-Up Current (Input Voltage = 0 V)	I_{PU}	V_{IO} = 1.8	–6	–3.5	–2	µA
		V_{IO} = 3.6	–30	–20	–10	µA
Input Leakage (Pullups off or Analog)	I_{LK}	0 ≤ V_{IN} ≤ V_{IO}	–1	—	1	µA
Input Leakage Current of Port Bank 3 I/O, V_{IN} above V_{IO}	I_L	V_{IO} < V_{IN} < V_{IO}+2.0 V (pins without EXREG functions)	0	5	150	µA
		V_{IO} < V_{IN} < V_{REGIN} (pins with EXREG functions)	0	5	150	µA
High Drive I/O (PB4)						
Output High Voltage	V_{OH}	Standard Mode, Low Drive, I_{OH} = –3 mA	V_{IOHD} – 0.7	—	—	V
		Standard Mode, High Drive, I_{OH} = –10 mA	V_{IOHD} – 0.7	—	—	V
Output Low Voltage	V_{OL}	Standard Mode, Low Drive, I_{OH} = 3 mA	—	—	0.6	V
		Standard Mode, High Drive, I_{OH} = 12.5 mA	—	—	0.6	V
Output Rise Time	t_R	Slew Rate Mode 0, V_{IOHD} = 5 V	—	50	—	ns
		Slew Rate Mode 1, V_{IOHD} = 5 V	—	300	—	ns
		Slew Rate Mode 2, V_{IOHD} = 5 V	—	1	—	µs
		Slew Rate Mode 3, V_{IOHD} = 5 V	—	3	—	µs

***Note:** $\overline{\text{RESET}}$ does not drive to logic high. Specifications for $\overline{\text{RESET}}$ V_{OL} adhere to the low drive setting.

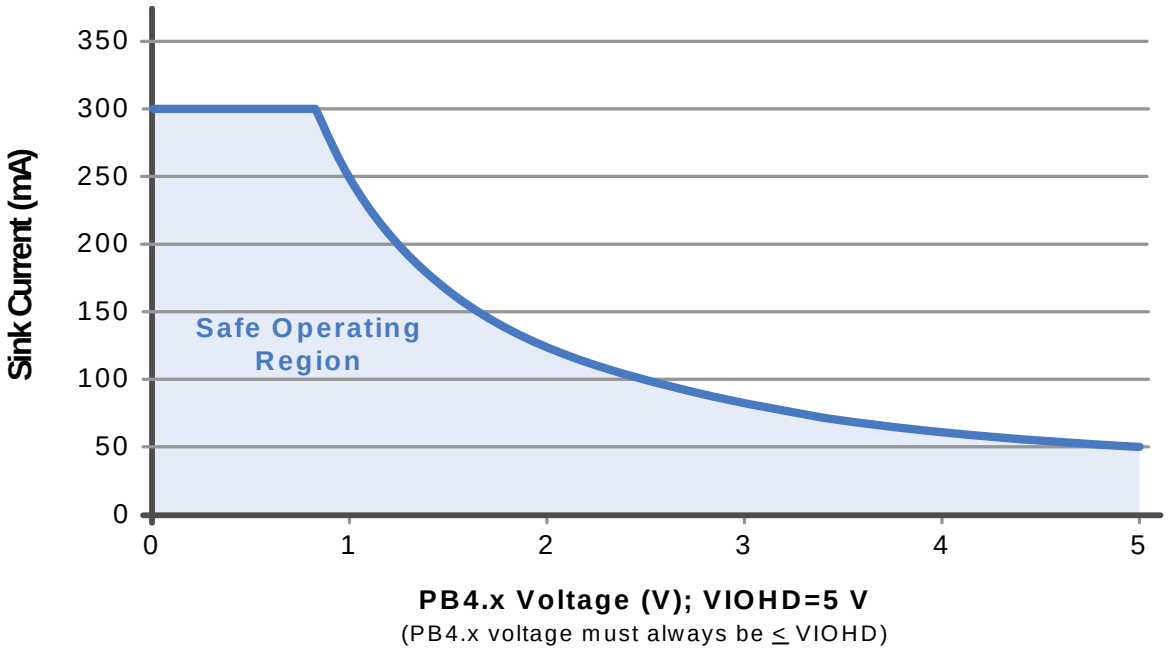


Figure 3.1. Maximum Sink Current vs. PB4.x Pin Voltage

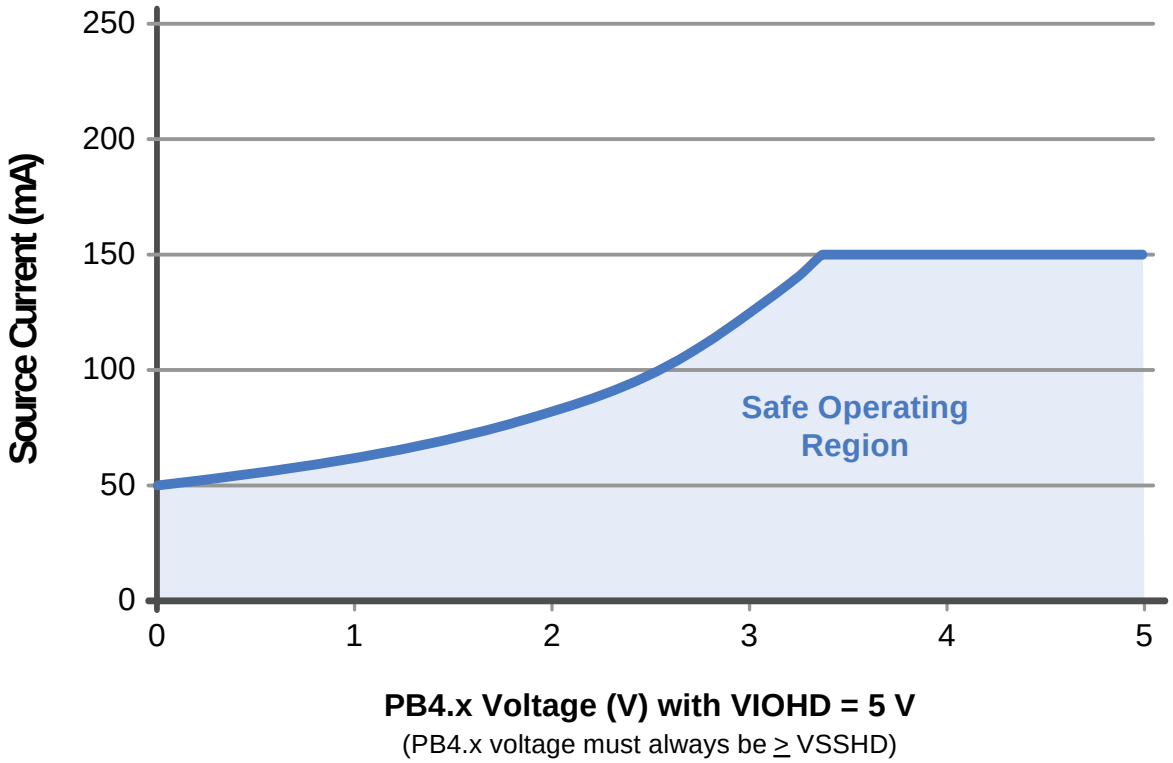


Figure 3.2. Maximum Source Current vs. PB4.x Pin Voltage

3.2. Thermal Conditions

Table 3.18. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance*	θ_{JA}	LGA-92 Packages	—	35	—	°C/W
		TQFP-80 Packages	—	40	—	°C/W
		QFN-64 Packages	—	25	—	°C/W
		TQFP-64 Packages	—	30	—	°C/W
		QFN-40 Packages	—	30	—	°C/W
***Note:** Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.						

3.3. Absolute Maximum Ratings

Stresses above those listed under Table 3.19 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

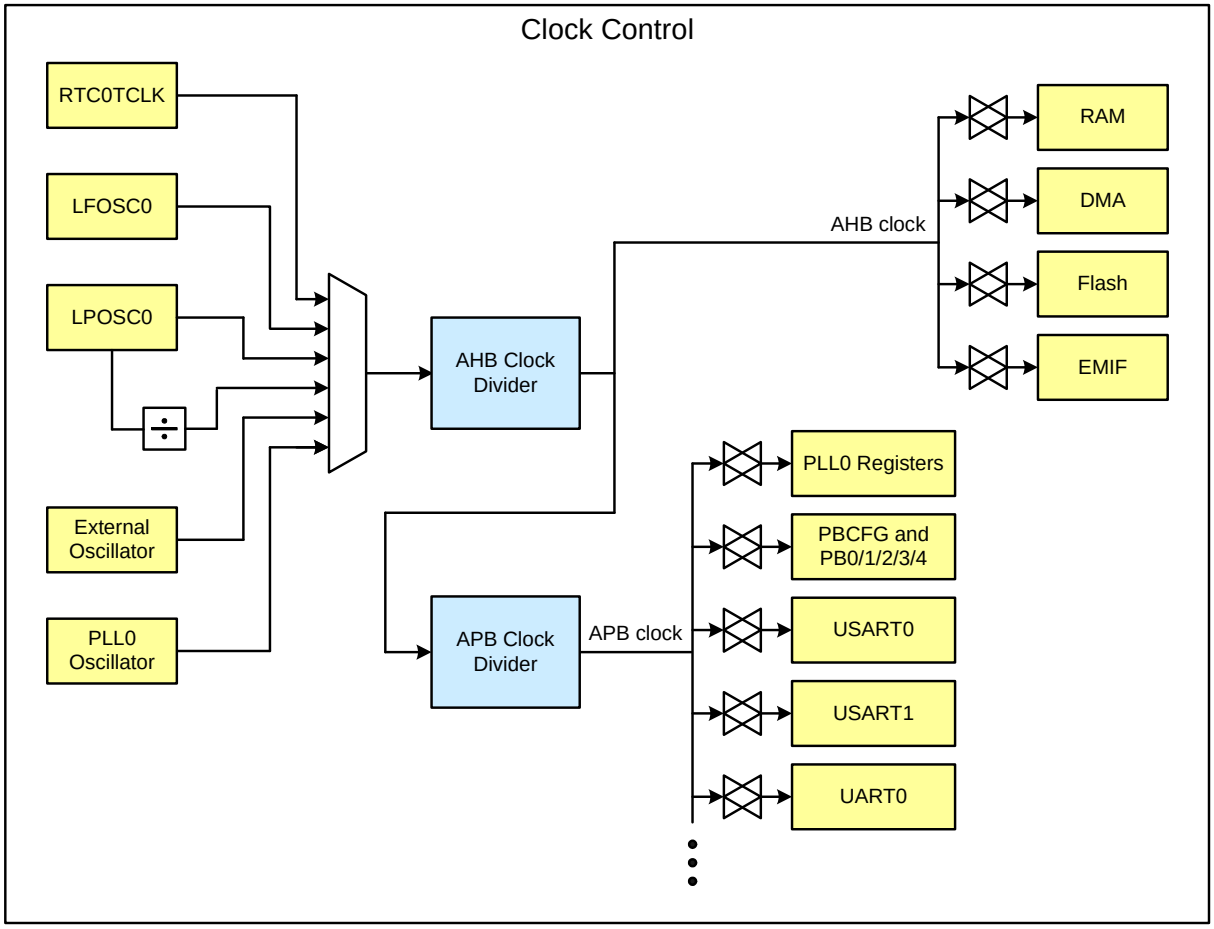
Table 3.19. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		–55	125	°C
Storage Temperature	T_{STG}		–65	150	°C
Voltage on VDD	V_{DD}		V_{SS}–0.3	4.2	V
Voltage on VREGIN	V_{REGIN}	EXTVREG0 Not Used	V_{SS}–0.3	6.0	V
		EXTVREG0 Used	V_{SS}–0.3	3.6	V
Voltage on VIO	V_{IO}		V_{SS}–0.3	4.2	V
Voltage on VIOHD	V_{IOHD}		V_{SS}–0.3	6.5	V
Voltage on I/O pins, non Port Bank 3 I/O	V_{IN}	$\overline{\text{RESET}}$, $V_{IO} \geq 3.3$ V	V_{SS}–0.3	5.8	V
		$\overline{\text{RESET}}$, $V_{IO} < 3.3$ V	V_{SS}–0.3	V_{IO}+2.5	V
		Port Bank 0, 1, and 2 I/O	V_{SS}–0.3	V_{IO}+0.3	V
		Port Bank 4 I/O	V_{SSHD}–0.3	V_{IOHD}+0.3	V
***Note:** VSS and VSSHD provide separate return current paths for device supplies, but are not isolated. They must always be connected to the same potential on board.					

4.3. Clocking

The SiM3C1xx devices have two system clocks: AHB and APB. The AHB clock services memory peripherals and is derived from one of seven sources: the RTC0 timer clock (RTC0TCLK), the Low Frequency Oscillator, the Low Power Oscillator, the divided Low Power Oscillator, the External Oscillator, and the PLL0 Oscillator. In addition, a divider for the AHB clock provides flexible clock options for the device. The APB clock services data peripherals and is synchronized with the AHB clock. The APB clock can be equal to the AHB clock (if AHB is less than or equal to 50 MHz) or set to the AHB clock divided by two.

Clock Control allows the AHB and APB clocks to be turned off to unused peripherals to save system power. Any registers in a peripheral with disabled clocks will be unable to be accessed until the clocks are enabled. Most peripherals have clocks off by default after a power-on reset.



4.3.1. PLL (PLL0)

The PLL module consists of a dedicated Digitally-Controlled Oscillator (DCO) that can be used in Free-Running mode without a reference frequency, Frequency-Locked to a reference frequency, or Phase-Locked to a reference frequency. The reference frequency for Frequency-Lock and Phase-Lock modes can use one of multiple sources (including the external oscillator) to provide maximum flexibility for different application needs. Because the PLL module generates its own clock, the DCO can be locked to a particular reference frequency and then moved to Free-Running mode to reduce system power and noise.

The PLL module includes the following features:

- Five output ranges with output frequencies ranging from 23 to 80 MHz.
- Multiple reference frequency inputs.
- Three output modes: free-running DCO, frequency-locked, and phase-locked.
- Ability to sense the rising edge or falling edge of the reference source.
- DCO frequency LSB dithering to provide finer average output frequencies.
- Spectrum spreading to reduce generated system noise.
- Low jitter and fast lock times.
- Ability to suspend all output frequency updates (including dithering and spectrum spreading) using the STALL bit during jitter-sensitive operations.

4.3.2. Low Power Oscillator (LPOSC0)

The Low Power Oscillator is the default AHB oscillator on SiM3C1xx devices and enables or disables automatically, as needed.

The Low Power Oscillator has the following features:

- 20 MHz and divided 2.5 MHz frequencies available for the AHB clock.
- Automatically starts and stops as needed.

4.3.3. Low Frequency Oscillator (LFOSC0)

The low frequency oscillator (LFOSC0) provides a low power internal clock source running at approximately 16.4 kHz for the RTC0 timer and other peripherals on the device. No external components are required to use the low frequency oscillator

4.3.4. External Oscillators (EXTOSC0)

The EXTOSC0 external oscillator circuit may drive an external crystal, ceramic resonator, capacitor, or RC network. A CMOS clock may also provide a clock input. The external oscillator output may be selected as the AHB clock or used to clock other modules independent of the AHB clock selection.

The External Oscillator control has the following features:

- Support for external crystal, RC, C, or CMOS oscillators.
- Support external CMOS frequencies from 10 kHz to 50 MHz and external crystal frequencies from 10 kHz to 30 MHz.
- Various drive strengths for flexible crystal oscillator support.
- Internal frequency divide-by-two option available.

4.5.3. Real-Time Clock (RTC0)

The RTC0 module includes a 32-bit timer that allows up to 36 hours of independent time-keeping when used with a 32.768 kHz watch crystal. The RTC0 provides three alarm events in addition to a missing clock event, which can also function as interrupt, reset, or wakeup sources on SiM3C1xx devices.

The RTC0 module includes internal loading capacitors that are programmable to 16 discrete levels, allowing compatibility with a wide range of crystals.

The RTC0 output can be buffered and routed to a port bank pin to provide an accurate, low frequency clock to other devices while the core is in its lowest power down mode. The module also includes a low power internal low frequency oscillator that reduces low power mode current and is available for other modules to use as a clock source.

The RTC module includes the following features:

- 32-bit timer (supports up to 36 hours) with three separate alarms.
- Option for one alarm to automatically reset the RTC timer.
- Missing clock detector.
- Can be used with the internal low frequency oscillator (LFOSC0), an external 32.768 kHz crystal (no additional resistors or capacitors necessary), or with an external CMOS clock.
- Programmable internal loading capacitors support a wide range of external 32.768 kHz crystals.
- Operates directly from VDD and remains operational even when the device goes into its lowest power down mode.
- The RTC timer clock (RTC0TCLK) can be buffered and routed to an I/O pin to provide an accurate, low frequency clock to other devices while the core is in its lowest power down mode.

4.5.4. Low Power Timer (LPTIMER0)

The Low Power Timer (LPTIMER0) module runs from the clock selected by the RTC0 module, allowing the LPTIMER0 to operate even if the AHB and APB clocks are disabled. The LPTIMER0 counter can increment using one of two clock sources: the clock selected by the RTC0 module, or rising or falling edges of an external signal.

The Low Power Timer includes the following features:

- Runs on a low-frequency clock (RTC0TCLK)
- The LPTIMER counter can increment using one of two clock sources: the RTC0TCLK or rising or falling edges of an external signal.
- Overflow and threshold-match detection, which can generate an interrupt, reset the timer, or wake some devices from low power modes.
- Timer reset on threshold-match allows square-wave generation at a variable output frequency.

4.5.5. Watchdog Timer (WDTIMER0)

The WDTIMER0 module includes a 16-bit timer, a programmable early warning interrupt, and a programmable reset period. The timer registers are protected from inadvertent access by an independent lock and key interface.

The watchdog timer runs from the low frequency oscillator (LFOSC0).

The Watchdog Timer has the following features:

- Programmable timeout interval.
- Optional interrupt to warn when the Watchdog Timer is nearing the reset trip value.
- Lock-out feature to prevent any modification until a system reset.

4.7. Analog

4.7.1. 12-Bit Analog-to-Digital Converters (SARADC0, SARADC1)

The SARADC0 and SARADC1 modules on SiM3C1xx devices are Successive Approximation Register (SAR) Analog to Digital Converters (ADCs). The key features of the SARADC module are:

- Single-ended 12-bit and 10-bit modes.
- Supports an output update rate of 250 k samples per second in 12-bit mode or 1 M samples per second in 10-bit mode.
- Operation in low power modes at lower conversion speeds.
- Selectable asynchronous hardware conversion trigger with hardware channel select.
- Output data window comparator allows automatic range checking.
- Support for Burst Mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete, multiple conversion complete, and FIFO overflow and underflow flags and interrupts supported.
- Flexible output data formatting.
- Sequencer allows up to 8 sources to be automatically scanned using one of four channel characteristic profiles without software intervention.
- Eight-word conversion data FIFO for DMA operations.
- Multiple SARADC modules can work together synchronously or by interleaving samples.
- Includes two internal references (1.65 V fast-settling, 1.2/2.4 V precision), support for an external reference, and support for an external signal ground.

4.7.2. Sample Sync Generator (SSG0)

The SSG module includes a phase counter and a pulse generator. The phase counter is a 4-bit free-running counter clocked from the SARADC module clock. Counting-up from zero, the phase counter marks sixteen equally-spaced events for any number of SARADC modules. The ADCs can use this phase counter to start a conversion. The programmable pulse generator creates a 50% duty cycle pulse with a period of 16 phase counter ticks. Up to four programmable outputs available to external devices can be driven by the pulse generator with programmable polarity and a defined output setting when the pulse generator is stopped.

The Sample Sync Generator module has the following features:

- Connects multiple modules together to perform synchronized actions.
- Outputs a clock synchronized to the internal sampling clock used by any number of SARADC modules to pins for use by external devices.
- Includes a phase counter, pulse generator, and up to four programmable outputs.

4.7.3. 10-Bit Digital-to-Analog Converter (IDAC0, IDAC1)

The IDAC takes a digital value as an input and outputs a proportional constant current on a pin. The IDAC module includes the following features:

- 10-bit current DAC with support for four timer, up to seven external I/O, on demand, and SSG0 output update triggers.
- Ability to update on rising, falling, or both edges for any of the external I/O trigger sources (DACnTx).
- Supports an output update rate greater than 600 k samples per second.
- Support for three full-scale output modes: 0.5 mA, 1.0 mA and 2.0 mA.
- Four-word FIFO to aid with high-speed waveform generation or DMA interactions.
- Individual FIFO overrun, underrun, and went-empty interrupt status sources.
- Support for multiple data packing formats, including: single 10-bit sample per word, dual 10-bit samples per word, or four 8-bit samples per word.
- Support for left- and right-justified data.

6.2. SiM3C1x6 Pin Definitions

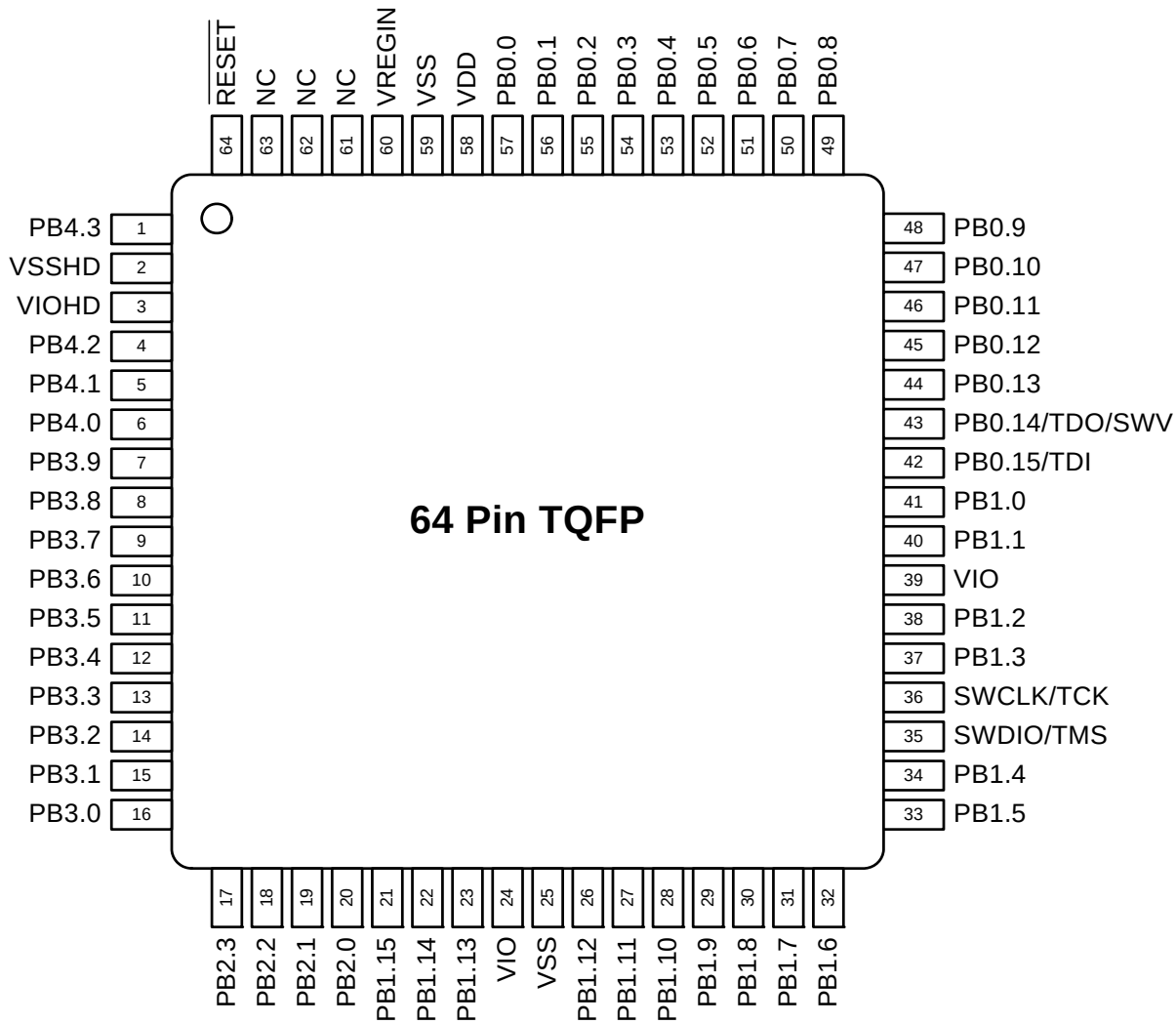


Figure 6.3. SiM3C1x6-GQ Pinout

Table 6.2. Pin Definitions and alternate functions for SiM3C1x6 (Continued)

Pin Name	Type	Pin Numbers	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB0.7	Standard I/O	50	XBR0	✓					RTC2
PB0.8	Standard I/O	49	XBR0	✓					ADC0.9 VREFGND
PB0.9	Standard I/O	48	XBR0	✓					ADC0.10 VREF
PB0.10	Standard I/O	47	XBR0	✓					ADC1.6 IDAC0
PB0.11	Standard I/O	46	XBR0	✓					IDAC1
PB0.12	Standard I/O	45	XBR0	✓					XTAL1
PB0.13	Standard I/O	44	XBR0	✓					XTAL2
PB0.14/TDO/ SWV	Standard I/O / JTAG / Serial Wire Viewer	43	XBR0	✓					ADC0.12 ADC1.12
PB0.15/TDI	Standard I/O / JTAG	42	XBR0	✓					ADC0.13 ADC1.13
PB1.0	Standard I/O	41	XBR0	✓					ADC0.14 ADC1.14
PB1.1	Standard I/O	40	XBR0	✓					ADC0.15 ADC1.15
PB1.2	Standard I/O	38	XBR0	✓					ADC1.11 CS0.8
PB1.3	Standard I/O	37	XBR0	✓					ADC1.10 CS0.9
PB1.4	Standard I/O	34	XBR0	✓					ADC1.8
PB1.5	Standard I/O	33	XBR0	✓					ADC1.7
PB1.6	Standard I/O	32	XBR0	✓				ADC0T15 WAKE.0	ADC1.5 CS0.10
PB1.7	Standard I/O	31	XBR0	✓	AD15m/ A7			ADC1T15 WAKE.1	ADC1.4 CS0.11

6.4. LGA-92 Package Specifications

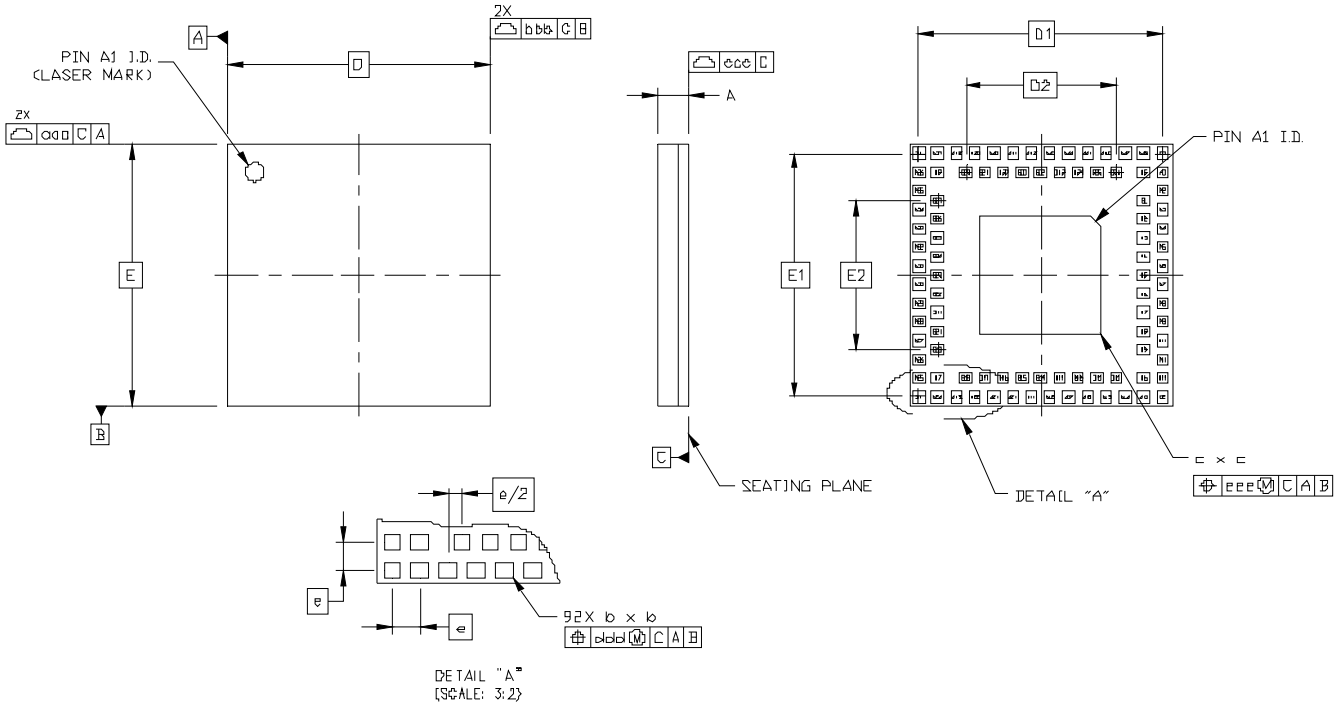


Figure 6.6. LGA-92 Package Drawing

Table 6.4. LGA-92 Package Dimensions

Dimension	Min	Nominal	Max
A	0.74	0.84	0.94
b	0.25	0.30	0.35
c	3.15	3.20	3.25
D		7.00 BSC	
D1		6.50 BSC	
D2		4.00 BSC	
e		0.50 BSC	
E		7.00 BSC	
E1		6.50 BSC	
E2		4.00 BSC	
aaa	—	—	0.10
bbb	—	—	0.10
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.10

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.5.1. TQFP-80 Solder Mask Design

All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

6.5.2. TQFP-80 Stencil Design

1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 1:1 for all pads.

6.5.3. TQFP-80 Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

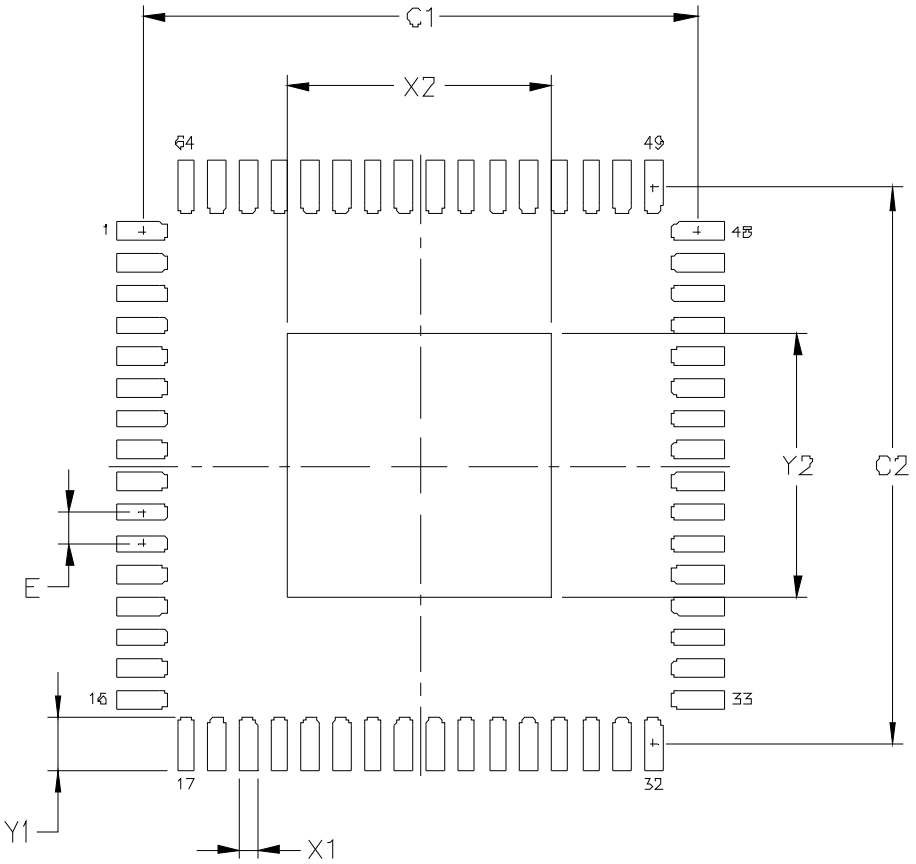


Figure 6.11. QFN-64 Landing Diagram

Table 6.9. QFN-64 Landing Diagram Dimensions

Dimension	mm
C1	8.90
C2	8.90
E	0.50
X1	0.30
Y1	0.85
X2	4.25
Y2	4.25

Notes:
1. All dimensions shown are in millimeters (mm).
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

6.8. QFN-40 Package Specifications

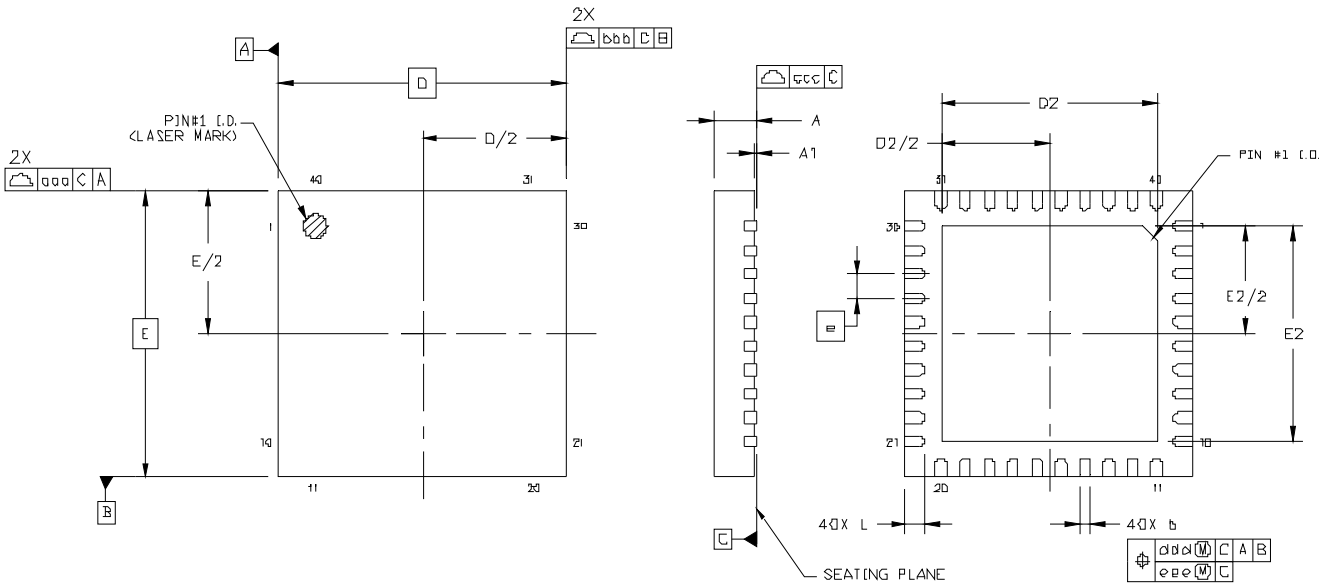


Figure 6.14. QFN-40 Package Drawing

Table 6.12. QFN-40 Package Dimensions

Dimension	Min	Nominal	Max
A	0.80	0.85	0.90
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D		6.00 BSC	
D2	4.35	4.50	4.65
e		0.50 BSC	
E		6.00 BSC	
E2	4.35	4.5	4.65
L	0.30	0.40	0.50
aaa		0.10	
bbb		0.10	
ccc		0.08	
ddd		0.10	
eee		0.05	

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This package outline conforms to JEDEC MO-220.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

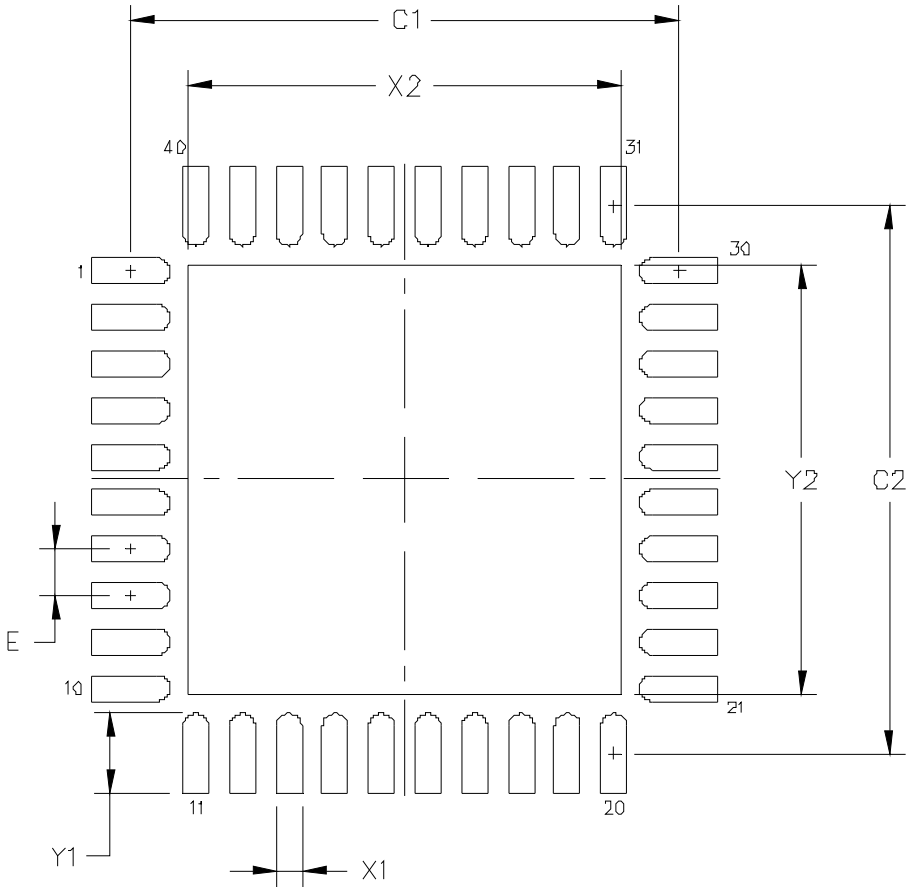


Figure 6.15. QFN-40 Landing Diagram

Table 6.13. QFN-40 Landing Diagram Dimensions

Dimension	mm
C1	5.90
C2	5.90
E	0.50
X1	0.30
Y1	0.85
X2	4.65
Y2	4.65

Notes:
1. All dimensions shown are in millimeters (mm).
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.